TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

2SK3316

Switching Regulator Applications

• Fast reverse recovery time $t_{rr} = 60 \text{ ns (typ.)}$

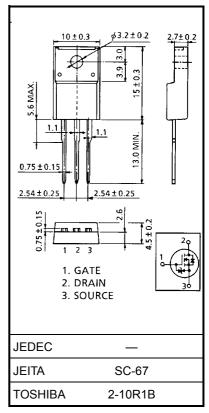
• Built-in high-speed free-wheeling diode

 $\begin{array}{ll} \bullet & Low\ drain-source\ ON\ resistance & : RDS\ (ON) = 1.6\ \Omega\ (typ.) \\ \bullet & High\ forward\ transfer\ admittance & : |Y_{fs}| = 3.8\ S\ (typ.) \\ \bullet & Low\ leakage\ current & : IDSS = 100\ \mu A\ (max)\ (V_{DS} = 500\ V) \\ \bullet & Enhancement-mode & : V_{th} = 2.0 \sim 4.0\ V\ (V_{DS} = 10\ V,\ I_D = 1\ mA) \end{array}$

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	500	V	
Drain-gate voltage (R	_{GS} = 20 kΩ)	V_{DGR}	500	V	
Gate-source voltage		V _{GSS}	±30	V	
Drain current	DC (Note 1)	I _D	5	Α	
	Pulse (Note 1)	I_{DP}	20	Α	
Drain power dissipation	n (Tc = 25°C)	P_{D}	35	W	
Single pulse avalanche energy (Note 2)		E _{AS}	180	mJ	
Avalanche current		I _{AR}	5	Α	
Repetitive avalanche e	nergy (Note 3)	E _{AR}	3.5	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature ra	ange	T _{stg}	-55~150	°C	

Unit: mm



Weight: 1.9 g (typ.)

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	3.57	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: V_{DD} = 90 V, T_{ch} = 25°C (initial), L = 12.2 mH, R_G = 25 Ω , I_{AR} = 5 A

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device.

Please handle with caution.

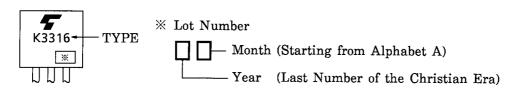
Electrical Characteristics (Ta = 25°C)

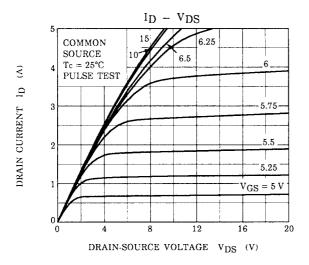
Charac	teristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±25 V, V _{DS} = 0 V	_	_	±10	μΑ
Gate-source bre	eakdown voltage	V _(BR) GSS	$I_G = \pm 100 \mu\text{A}, V_{DS} = 0 \text{V}$	±30	_	_	V
Drain cut-off cu	rent	I _{DSS}	V _{DS} = 500 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	500	_	_	V
Gate threshold v	roltage	V_{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source O	N resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 2.5 A	_	1.6	1.8	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 2.5 A	2.5	3.8	_	S
Input capacitano	е	C _{iss}		_	780	_	
Reverse transfer	capacitance	C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	60	_	pF
Output capacitance		C _{oss}			200	_	
Switching time	Rise time	tr	$V_{\rm GS}$ $V_{\rm GS}$ $V_{\rm OUT}$ $V_{\rm DD}$ $V_{\rm DD}$ $V_{\rm DD}$	_	12	_	- ns
	Turn-on time	t _{on}		1	25	1	
	Fall time	t _f			15		
	Turn-off time	t _{off}	Duty $\leq 1\%$, $t_{\rm W} = 10 \mu \rm s$	1	60	1	
Total gate charge (Gate-source plus gate-drain)		Qg			17		
Gate-source charge		Q_{gs}	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		11	_	nC
Gate-drain ("miller") charge		Q _{gd}		_	6	_	

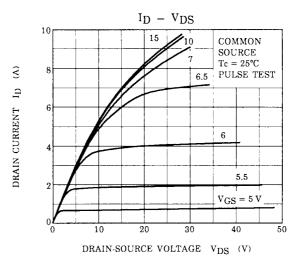
Source-Drain Ratings and Characteristics (Ta = 25°C)

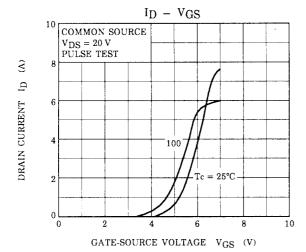
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	5	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	20	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 5 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 5 A, V _{GS} = 0 V, dI _{DR} / dt = 100 A / μs	_	60	_	ns
Reverse recovery charge	Q _{rr}	1DR - 3 A, VGS - 0 V, αιDR / αι - 100 A / μs		0.1	_	μC

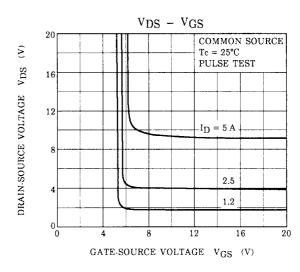
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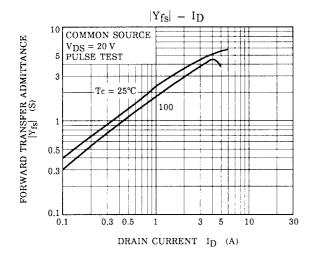


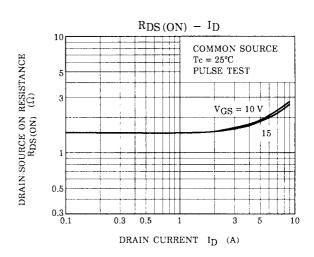




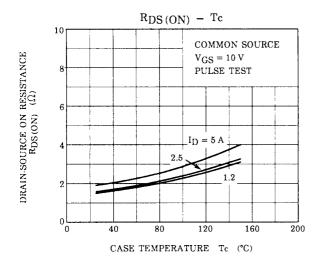


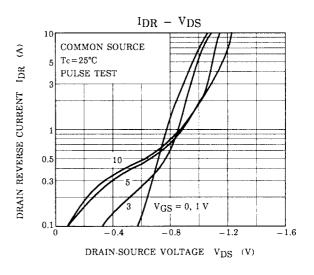


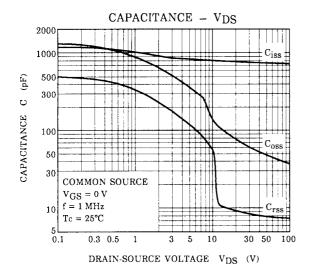


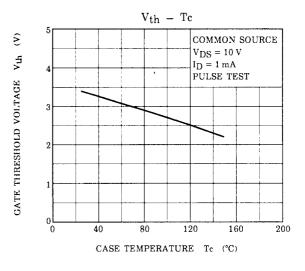


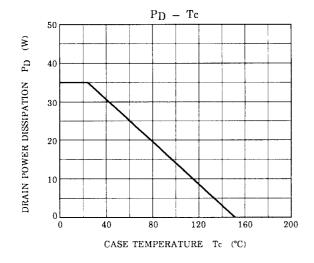
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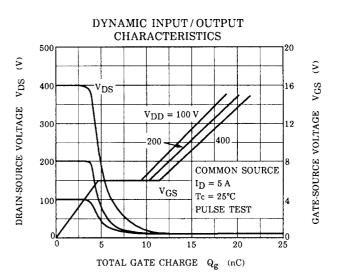




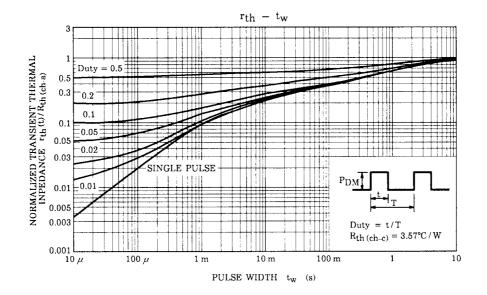


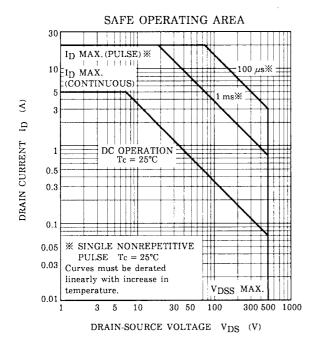


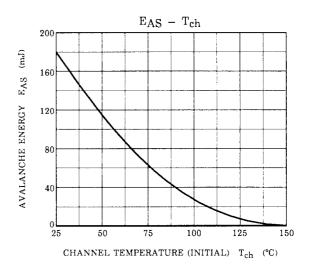


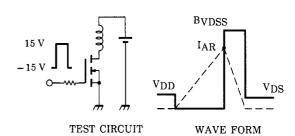


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$$\begin{aligned} R_G &= 25~\Omega,~V_{DD} = 90~V \\ L &= 12.2~mH \end{aligned} \qquad E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - V_{DD}} \right) \end{aligned}$$

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